

(12) **United States Patent**
Zeng et al.

(10) **Patent No.:** **US 9,917,344 B2**
(45) **Date of Patent:** **Mar. 13, 2018**

(54) **NONUNIFORM CORRUGATED DIAPHRAGM FOR MEMS TUNERS AND ACTUATORS**

(2013.01); **H01P 1/2053** (2013.01); **H01P 7/065** (2013.01); **H03J 3/02** (2013.01); **H03H 2003/027** (2013.01)

(71) Applicant: **Purdue Research Foundation**, West Lafayette, IN (US)

(58) **Field of Classification Search**

CPC H01P 1/205; H01P 1/2053; H01P 7/06; H01P 1/208; H01P 7/065; H03H 2003/027; H03J 3/02
USPC 333/209, 227, 231–233
See application file for complete search history.

(72) Inventors: **Juan Zeng**, West Lafayette, IN (US); **Zhengan Yang**, West Lafayette, IN (US); **Dimitrios Peroulis**, West Lafayette, IN (US)

(56) **References Cited**

U.S. PATENT DOCUMENTS

2,409,321 A * 10/1946 Ingo H01P 7/06 220/720
8,087,152 B2 * 1/2012 Kato B81C 1/0038 29/594

(Continued)

(73) Assignee: **PURDUE RESEARCH FOUNDATION**, West Lafayette, IN (US)

(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 140 days.

(21) Appl. No.: **15/098,969**

OTHER PUBLICATIONS

(22) Filed: **Apr. 14, 2016**

Z. Yang and D. Peroulis, "A 23-35 GHz MEMS tunable all-silicon cavity filter with stability characterization up to 140 million cycles," in IEEE MTT-S International Microwave Symposium (IMS), Jun. 2014, pp. 1-4.

(Continued)

(65) **Prior Publication Data**
US 2016/0336922 A1 Nov. 17, 2016

Related U.S. Application Data

Primary Examiner — Rakesh Patel

(60) Provisional application No. 62/147,111, filed on Apr. 14, 2015.

(74) *Attorney, Agent, or Firm* — Purdue Research Foundation

(51) **Int. Cl.**
H01P 7/06 (2006.01)
H01P 1/208 (2006.01)
H03J 3/02 (2006.01)
H01P 1/205 (2006.01)
H01H 59/00 (2006.01)
H03H 3/02 (2006.01)

(57) **ABSTRACT**

A cavity resonator tuning diaphragm comprising a plurality of inner corrugations, the plurality of inner corrugations having a first depth. An outer corrugation located between the plurality of inner corrugations and a perimeter of the diaphragm is also included, the outer corrugation having a second depth greater than the first depth. The addition of the outer deep corrugation provides increased thermal stability and reduced required actuation voltage.

(52) **U.S. Cl.**
CPC **H01P 7/06** (2013.01); **H01H 59/00** (2013.01); **H01P 1/205** (2013.01); **H01P 1/208**

10 Claims, 13 Drawing Sheets

